


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/708,444	HWANG ET AL.	
	Examiner	Art Unit	
	Yaima Campos	2185	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EIC PLUS search	3/10/2006	YC
PALM and EAST inventor name search	3/10/2006	YC
Text search within subclasses 711/115,156	3/10/2006	YC